Notice of References Cited Application/Control No. 10/615,404 Examiner TAN X. DINH Applicant(s)/Patent Under Reexamination ONOE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,481,527 a	01-1996	Kasanuki et al.	369/126
	В	US-6,912,193 b2	06-2005	Cho et al.	369/126
	С	US-5,418,029 a	05-1995	Yamamoto et al.	428/64.2
	D	US-5,946,284 a	08-1999	Chung et al.	369/126
	E	US-5,777,977 a	07-1998	Fujiwara et al.	369/126
	F	US-6,841,220 b2	01-2005	Onoe et al.	428/66.7
	G	US-2004/0114913 a1	06-2004	Kume, Hidehiro	386/125
	Н	US-2004/0263185 a1	12-2004	Cho et al.	324/636
	ı	US-2004/0027935 a1	02-2004	Cho et al.	369/126
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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